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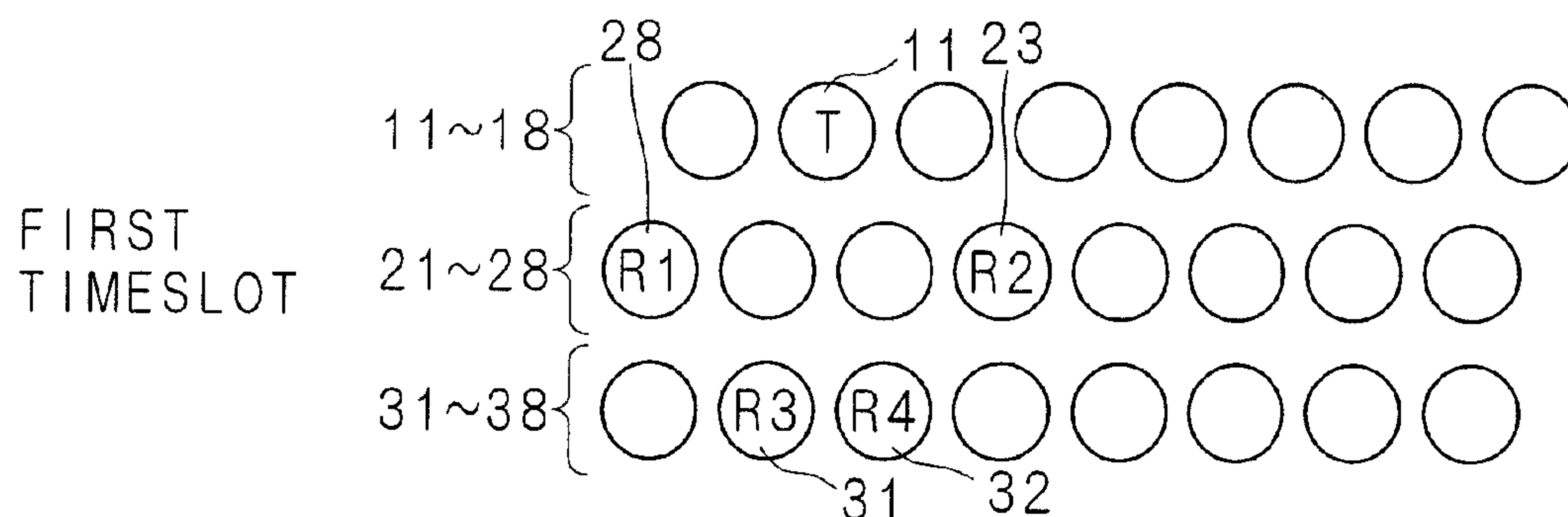
(72) Inventeurs/Inventors:
HARADA, YUTAKA, JP;
SHIMONE, JUNRI, JP;
MAEDA, KOTARO, JP

(73) Propriétaire/Owner:
NUCLEAR ENGINEERING, LTD., JP

(74) Agent: RIDOUT & MAYBEE LLP

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(54) Title: EDDY-CURRENT FLAW DETECTION METHOD, EDDY-CURRENT FLAW DETECTION DEVICE AND EDDY-CURRENT FLAW DETECTION PROBE



(57) Abrégé/Abstract:

An eddy-current flaw detection device including magnetic elements evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it can be inserted into a conductive pipe. A first row is located at a position that differs from a second row by 1/2 the even spacing in the row direction. Switching circuits switch the magnetic elements in the respective row of the magnetic element group at each time slot. During a given time slot, a given magnetic element in the first row is switched to excite a magnetic field, and two magnetic elements of the second row, which are located at positions that differ from the given magnetic element by 3/2 the even spacing, function as magnetic field detection elements that detect a magnetic field.



ABSTRACT

An eddy-current flaw detection device including magnetic elements evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it
5 can be inserted into a conductive pipe. A first row is located at a position that differs from a second row by $1/2$ the even spacing in the row direction. Switching circuits switch the magnetic elements in the respective row of the magnetic element group at each time slot. During a given time slot, a given magnetic element in the first
10 row is switched to excite a magnetic field, and two magnetic elements of the second row, which are located at positions that differ from the given magnetic element by $3/2$ the even spacing, function as magnetic field detection elements that detect a magnetic field.

EDDY-CURRENT FLAW DETECTION METHOD,
EDDY-CURRENT FLAW DETECTION DEVICE AND
EDDY-CURRENT FLAW DETECTION PROBE

5

BACKGROUND

1. Technical Field

[0001]

10 The present invention relates to improvements of an eddy-current flaw detection method, eddy-current flaw detection device and eddy-current flaw detection probe that are used in nondestructive inspection (eddy-current flaw detection testing) of a heat transfer pipe inside of a heat exchanger.

15

2. Description of Related Art

[0002]

FIG. 1 is a perspective drawing schematically illustrating the external appearance of a conventional eddy-current flaw
20 detection probe that is used in an eddy-current flaw detection device for a slim metal pipe, which is a heat transfer pipe (conductive pipe) inside of a heat exchanger.

Eddy-current flaw detection testing is a nondestructive inspection that applies a magnetic field that changes over time (AC
25 current or the like) to a conductor, and detects when an eddy

current, which occurs in the conductor, changes due to flaws; and in eddy-current flaw detection testing of a slim metal pipe, detection is performed while moving an eddy-current flaw detection probe that has been gently inserted inside the slim metal pipe.

5 [0003]

This eddy-current flaw detection probe comprises a column-shaped casing (housing) 141 that is formed such that it can be gently inserted inside a slim metal pipe, and eight coils 111 to 118, 121 to 128, 131 to 138, that are aligned around the outer
10 surface of the casing 141, are evenly spaced in each of three rows. The coils 111 to 118 of the first row of the three rows are arranged such that they are located at a position in the circumferential direction that differs from that of the coils 121 to 128 and 131 to 138 of the other two rows by 1/2 the equal spacing between coils.

15 [0004]

FIG. 2 is a block diagram illustrating the circuit construction inside the casing 141 and eddy-current flaw detection device.

The coils 111 to 118 in the first row are coils that are jointly
20 used as magnetic field excitation coils and magnetic field detection coils, and each of these is connected to a multiplexer (switching circuit) 151 for magnetic field excitation, and to a multiplexer (switching circuit) 152 for magnetic field detection.

A lead wire 159 is connected to the multiplexer 151 for
25 magnetic field excitation, and an AC current for exciting a

magnetic field is applied to the lead wire 159 from the main unit 164 of the eddy-current flaw detection device. An amplifier 156, which amplifies the output signal of the magnetic field that is detected by the coils 111 to 118, is connected to the multiplexer 152 for magnetic field detection, and the signal that is amplified by the amplifier 156 is outputted to the main unit 164 of the eddy-current flaw detection device via a lead wire 160.

[0005]

Moreover, the coils 121 to 128 in the second row are also coils that are jointly used as magnetic field excitation coils and magnetic field detection coils, and each of these coils is connected to a multiplexer (switching circuit) 153 for magnetic field excitation, and to a multiplexer (switching circuit) 154 for magnetic field detection.

A lead wire 161 is connected to the multiplexer 153 for magnetic field excitation, and an AC current for exciting a magnetic field is applied to the lead wire 161 from the main unit 164 of the eddy-current flaw detection device. An amplifier 157, which amplifies the output signal of the magnetic field that is detected by the coils 121 to 128, is connected to the multiplexer 154 for magnetic field detection, and the signal that is amplified by the amplifier 157 is outputted to the main unit 164 of the eddy-current flaw detection device via a lead wire 162.

[0006]

The coils 131 to 138 in the third row are magnetic field

detection coils, and each of these is connected to a multiplexer (switching circuit) 155 for magnetic field detection.

An amplifier 158, which amplifies the output signal of the magnetic field that is detected by the coils 131 to 138, is connected to the multiplexer 155 for magnetic field detection, and the signal that is amplified by the amplifier 158 is outputted to the main unit 164 of the eddy-current flaw detection device via a lead wire 163.

As shown in FIG. 1, the lead wires 159 to 163 are stored inside a cable 142 that connects the center section of the surface on one end of the casing 141 of the eddy-current flaw detection probe with the main unit 164 of the eddy-current flaw detection device.

[0007]

An oscillation circuit 165 that produces an AC current for exciting a magnetic field by coils 111 to 118 and 121 to 128, a signal detection circuit 166 that obtains amplified detection signals of magnetic fields that are detected by coils 111 to 118, 121 to 128 and 131 to 138, and a communication unit 167 for communicating with a personal computer (or workstation) 168 are stored inside of the main unit 164 of the eddy-current flaw detection device. The personal computer 168 receives the detection signal that was obtained by the signal detection circuit 166 via the communication unit 167 as detection data, and records and displays the received detection data.

[0008]

FIGS. 3A to 3D are expanded views explaining the

operation of an eddy-current flaw detection probe having this kind of construction, and illustrating a planar expansion of the coils 111 to 118, 121 to 128 and 131 to 138 shown in FIG. 1.

According to such eddy-current flaw detection probe, in a first timeslot representing operation cycle (FIG. 3A), the multiplexer 151 selects coil 111 as the magnetic field excitation coil T, and multiplexer 152 selects coil 113, which is located at a position that differs two coils amount ahead of coil 111 in the circumferential direction of selection, as the magnetic field detection coil R. In addition, multiplexer 155 selects coils 131 and 132 in the third row, which are separated from coil 111 by an amount of 0.5 coil in the circumferential direction, as magnetic field detection coils R.

[0009]

According to the eddy-current flaw detection probe, in a second timeslot (FIG. 3B), the multiplexer 153 selects coil 121 in the second row, which is located at a position that differs 0.5 coil amount behind coil 111 in the circumferential direction of selection, as the magnetic field excitation coil T, and the multiplexer 154 selects coil 123, which is located at a position that differs two coils amount ahead of coil 121 in the circumferential direction of selection, as the magnetic field detection coil R.

[0010]

After that, in odd number timeslots, the multiplexer 151 sequentially selects coils 112, 113, 114, ... as the magnetic field

excitation coil T, and the multiplexer 152 sequentially selects coils 114, 115, 116, ... as the magnetic field detection coil R. Moreover, the multiplexer 155 sequentially selects two coils 132·133, 133·134, 134·135, ... as magnetic field detection coils R.

5 In even number timeslots, the multiplexer 153 sequentially selects coils 122, 123, 124, ... as the magnetic field excitation coil T, and the multiplexer 154 sequentially selects coils 124, 125, 126 as the magnetic field detection coil R.

[0011]

10 According to the eddy-current flaw detection probe, in a fifteenth timeslot (FIG. 3C), the multiplexer 151 selects coil 118 as the magnetic field excitation coil T, and the multiplexer 152 selects coil 112, which is located at a position that differs two coils amount ahead of coil 118 in the circumferential direction of selection, as the
15 magnetic field detection coil R. In addition, the multiplexer 155 selects coils 138, 131 in the third row, which are separated from coil 118 by an amount of 0.5 coil in the circumferential direction, as magnetic field detection coils R.

[0012]

20 According to the eddy-current flaw detection probe, in a sixteenth timeslot (FIG. 3D), the multiplexer 153 selects coil 128 in the second row, which is located at a position that differs 0.5 coil amount behind coil 118 in the circumferential direction of selection, as the magnetic field excitation coil T, and the multiplexer 154
25 selects coil 122, which is located at a position that differs two coils

amount ahead of coil 128 in the circumferential direction of selection, as the magnetic field detection coil R.

[0013]

From the above, this flaw detection probe can obtain, for
5 each circumference around a slim metal pipe, eight channels of output from coils 111 to 118 for detecting flaws in the circumferential direction, eight channels of output from coils 121 to 128 for detecting flaws in the circumferential direction, and 16 channels of output from coils 131 to 138 for detecting flaws in the
10 axial direction. The output signals from coils 111 to 118 and the output signals from coils 121 to 128 are in a positional relationship that interpolate between each other in the circumferential direction, so the output for detecting flaws in the circumferential direction becomes a total of 16 channels.

15 [0014]

Japanese Patent Application Laid-Open No. 2000-235018 discloses an eddy-current flaw detection probe that comprises a plurality of excitation coils, a plurality of detection coils, and a switching circuit for time-division driving of these coils, and that
20 further comprises an insulation switching circuit between the coils and switching circuit.

Japanese Patent Application Laid-Open No. 2000-235019 discloses an eddy-current flaw detection probe that comprises a plurality of magnet field excitation elements, a plurality of
25 magnetic field detection elements, a switching circuit for

time-division driving of these elements, and a detection signal amplification circuit that is provided further on the measurement instrument side than the switching circuit that time-division drives the plurality of magnetic field detection elements.

5 [0015]

Japanese Patent Application Laid-Open No. 2000-235020 discloses an eddy-current flaw detection device that comprises an eddy-current flaw detection probe having a plurality of magnetic field excitation elements and magnetic field detection element
10 pairs, and means for time-division driving of the magnetic field excitation elements and magnetic field detection element pairs of that probe, and further comprises a control device that includes means for keeping output signals from each element pair over a number of time-division driving steps, and means for finding the
15 difference between the output signals from adjacent element pairs.

SUMMARY

[0016]

In the conventional eddy-current flaw detection probe
20 described above, there is a positional shift in the axial direction between the output of the 8 channels from coils 111 to 118 and the output of the 8 channels from coils 121 to 128 for detecting flaws in the circumferential direction, and when there is fluctuation in the scanning speed of the eddy-current flaw detection probe, it is
25 difficult to compensate for that positional shift in the axial

direction. When it is not possible to compensate for the positional shift in the axial direction, there are problems that the spatial resolution of the flaw detection signals drops, as well as the signal reproducibility during redetection of flaws drops.

5 Moreover, in the eddy-current flaw detection probe described above, coils 111 to 118 and 121 to 128 are jointly used as magnetic field excitation coils and magnetic field detection coils, and are connected to both a switching circuit for magnetic field excitation and a switching circuit for magnetic field detection, so
10 there are problems that circuit construction becomes complicated, and interference signals due to crosstalk occur.

[0017]

 The present invention has been made with the aim of solving the above problems, and it is an object of first to third
15 aspects of the invention to provide an eddy-current flaw detection method that improves the spatial resolution of flaw detection signals and the signal reproducibility during redetection of flaws, and reduces signal interference due to crosstalk with a simple circuit construction.

20 The object of fourth to ninth aspects of the invention is to provide an eddy-current flaw detection device that improves the spatial resolution of flaw detection signals and the signal reproducibility during redetection of flaws, and reduces signal interference due to crosstalk with a simple circuit construction.

25 The object of tenth to fifteenth aspects of the invention is to

provide an eddy-current flaw detection probe that improves the spatial resolution of flaw detection signals and the signal reproducibility during redetection of flaws, and reduces signal interference due to crosstalk with a simple circuit construction.

5 [0018]

The eddy-current flaw detection method according to a first aspect of the invention is an eddy-current flaw detection method for performing eddy-current flaw detection of a conductive pipe by using a magnetic element group of which a specified number of
10 elements are evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it can be inserted into the conductive pipe, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row direction, and
15 switching circuits for switching the magnetic elements in the respective row of the magnetic element group at time-division; and is characterized by comprising: a step of causing the switching circuit to switch magnetic elements in one row at time-division in order to excite a magnetic field; and a step of causing the switching
20 circuit to switch, at time-division, two of the magnetic elements that are arranged in the other row and that are located at positions that differ from the magnetic element that excited the magnetic field by $3/2$ the even spacing in the row direction in order to detect the excited magnetic field.

25 [0019]

The eddy-current flaw detection method according to a second aspect of the invention is an eddy-current flaw detection method for performing eddy-current flaw detection of a conductive pipe by using a magnetic element group of which a specified
5 number of elements are evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it can be inserted into the conductive pipe, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row direction, and
10 switching circuits for switching the magnetic elements in the respective row of the magnetic element group at time-division; and is characterized by comprising: a step of preparing the magnetic elements in one row as magnetic field excitation elements that excite a magnetic field, and the magnetic elements in the other row
15 as magnetic field detection elements that detect a magnetic field; a step of causing the switching circuit to switch magnetic field excitation elements at time-division in order to excite a magnetic field; and a step of causing the switching circuit to switch, at time-division, two of the magnetic field detection elements that are
20 arranged in the other row and that are located at positions that differ from the magnetic field excitation element that excited the magnetic field by $3/2$ the even spacing in the row direction in order to detect the excited magnetic field.

[0020]

25 The eddy-current flaw detection method according to a

third aspect of the invention is characterized by comprising: a step of preparing a magnetic element group that is located in a row around the surface of the casing adjacent to the other row, and a switching circuit for switching the magnetic element group at
5 time-division; and a step of causing the switching circuit to switch, at time-division, two magnetic elements that are located in the row in order to detect the excited magnetic field.

[0021]

The eddy-current flaw detection device according to a
10 fourth aspect of the invention is an eddy-current flaw detection device for performing eddy-current flaw detection of a conductive pipe, and comprising: a magnetic element group of which a specified number of magnetic elements are evenly spaced in each of at least two rows that are formed around the surface of a column
15 shaped casing that is formed such that it can be inserted into the conductive pipe, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row direction; and switching circuits for switching the magnetic elements in the respective row of the magnetic element group at
20 time-division, and is characterized by comprising: magnetic field excitation means for causing the magnetic elements in one row to function as magnetic field excitation elements that excite magnetic fields by being switched at time-division by the switching circuit; and magnetic field detection means for causing the magnetic
25 elements in the other row to function as magnetic field detection

elements that detect magnetic fields by being switched at time-division by the switching circuit, wherein the eddy-current flaw detection device performs eddy-current flaw detection of the conductive pipe by detecting each magnetic field that is excited by each magnetic field excitation element of the magnetic field excitation means by two magnetic field detection elements of the magnetic field detection means that are each located at positions that differ from that of the magnetic field excitation element by $3/2$ the even spacing in the row direction.

10 [0022]

In the eddy-current flaw detection method according to the first aspect of the invention and the eddy-current flaw detection device according to the fourth aspect of the invention, a magnetic element group is provided of which a specified number of magnetic elements are evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it can be inserted into the conductive pipe, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row direction, each switching circuit switches the magnetic elements in the respective row at time-division, and eddy-current flaw detection of the conductive pipe is performed. The magnetic elements in one row function as magnetic field excitation elements that excite magnetic fields by being switched at time-division, and magnetic elements in the other row function as magnetic field detection elements that

detect magnetic fields by being switched at time-division.

Eddy-current flaw detection of a conductive pipe is performed by detecting each magnetic field that is excited by each magnetic field excitation element by two of the magnetic field detection elements that are located at positions that differ from the magnetic field excitation element by $3/2$ the even spacing in the row direction.
[0023]

The eddy-current flaw detection device according to a fifth aspect of the invention is an eddy-current flaw detection device for performing eddy-current flaw detection of a conductive pipe, and comprising: a magnetic element group of which a specified number of magnetic elements are evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it can be inserted into the conductive pipe, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row direction; and switching circuits for switching the magnetic elements in the respective row of the magnetic element group at time-division, and is characterized in that the magnetic elements in one row are magnetic field excitation elements that excite magnetic fields, the magnetic elements in the other row are magnetic field detection elements that detect magnetic fields, and eddy-current flaw detection of the conductive pipe is performed by detecting each magnetic field that is excited by each magnetic field excitation element being switched at time-division by the switching circuit by

two magnetic field detection elements that are each located in the other row at positions that differ from the magnetic field excitation element by $3/2$ the even spacing in the row direction.

[0024]

5 In the eddy-current flaw detection method according to the second aspect of the invention and the eddy-current flaw detection device according to the fifth aspect of the invention, a magnetic element group is provided of which a specified number of magnetic elements are evenly spaced in each of at least two rows that are
10 formed around the surface of a column shaped casing that is formed such that it can be inserted into the conductive pipe, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row direction, each switching circuit switches the magnetic elements in the respective
15 row at time-division, and eddy-current flaw detection of the conductive pipe is performed. The magnetic elements in one row are magnetic field excitation elements that excite a magnetic field, and the magnetic elements in the other row are magnetic detection elements that detect a magnetic field. Eddy-current flaw
20 detection of the conductive pipe is performed by detecting each magnetic fields that are excited by each magnetic field excitation elements that are switched at time-division by two magnetic field detection elements that are each located in the other row at positions that differ from the magnetic field excitation element by
25 $3/2$ the even spacing in the row direction and that are switched at

time-division.

[0025]

The eddy-current flaw detection device according to a sixth aspect of the invention is an eddy-current flaw detection device comprising a magnetic element group of which a specified number of magnetic elements are evenly spaced in each of at least two rows, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row direction, and switching circuits for switching the magnetic elements in the respective row of the magnetic element group at time-division; and is characterized by comprising: magnetic field excitation means for causing the magnetic elements in one row to function as magnetic field excitation elements that excite magnetic fields by being switched at time-division by the switching circuit, and magnetic field detection means for causing the magnetic elements in the other row to function as magnetic field detection elements that detect magnetic fields by being switched at time-division by the switching circuit, wherein the eddy-current flaw detection device performs eddy-current flaw detection by detecting each magnetic field that is excited by each magnetic field excitation element of the magnetic field excitation means by one or two magnetic field detection elements of the magnetic field detection means that are each located at positions that differ from that of the magnetic field excitation element by $3/2$ the even spacing in the row direction.

[0026]

In the eddy-current flaw detection device according to the sixth aspect of the invention, a magnetic element group is provided of which a specified number of magnetic elements are evenly spaced in each of at least two rows, with one of the two rows being
5 located at a position that differs from the other row by $1/2$ the even spacing in the row direction, and each switching circuit switches the magnetic elements of each row at time-division. The magnetic elements in one row function as magnetic field excitation elements that excite a magnetic field by being switched at time-division, and
10 the magnetic elements in the other row function as magnetic detection elements that detect a magnetic field by being switched at time-division. Eddy-current flaw detection is performed by detecting each magnetic field that is excited by each magnetic field excitation element by one or two magnetic field detection elements
15 that are each located at positions that differ from the magnetic field excitation element by $3/2$ the even spacing in the row direction.

[0027]

The eddy-current flaw detection device according to a
20 seventh aspect of the invention is an eddy-current flaw detection device comprising: a magnetic element group of which a specified number of magnetic elements are evenly spaced in each of at least two rows, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row
25 direction; and switching circuits for switching the magnetic

elements in the respective row of the magnetic element group at time-division, and is characterized in that the magnetic elements in one row are magnetic field excitation elements that excite a magnetic field, the magnetic elements in the other row are

5 magnetic field detection elements that detect a magnetic field, and eddy-current flaw detection is performed by detecting each magnetic field that is excited by each magnetic field excitation element that is switched at time-division by the switching circuit by one or two magnetic field detection elements that are each

10 located in the other row at positions that differ from the magnetic field excitation element by $3/2$ the even spacing in the row direction and that are switched at time-division by the switching circuit.

[0028]

In the eddy-current flaw detection device according to the

15 seventh aspect of the invention, a magnetic element group is provided of which a specified number of magnetic elements are evenly spaced in each of at least two rows, with one of the two rows being located at a position that differs from the other row by $1/2$ the even spacing in the row direction, and each switching circuit

20 switches the magnetic elements in the respective row at time-division. The magnetic elements in one row are magnetic field excitation elements that excite a magnetic field, and the magnetic elements in the other row are magnetic field detection elements that detect a magnetic field. Eddy-current flaw

25 detection is performed by detecting each magnetic field that is

excited by each magnetic field excitation element that is switched
at time-division by one or two magnetic field detection elements
that are each located in the other row at positions that differ from
that of the magnetic field excitation element by $3/2$ the even
5 spacing in the row direction and that are switched at time-division.
[0029]

The eddy-current flaw detection device according to an
eighth aspect of the invention is characterized by further
comprising a magnetic element group that is located in a row
10 around the surface of the casing adjacent to the other row, and a
switching circuit for switching the magnetic element group at
time-division, and performing eddy-current flaw detection by
detecting an excited magnetic field by two magnetic elements that
are located in the row and that are switched by the switching
15 circuit.
[0030]

In the eddy-current flaw detection method according to the
third aspect of the invention and the eddy-current flaw detection
device according to the eighth aspect of the invention, another
20 magnetic element group is additionally located in a row around the
surface of the casing adjacent to the other row, and that
additionally provided magnetic element group is switched at
time-division by an additionally provided switching circuit.
Eddy-current flaw detection is performed by detecting an excited
25 magnetic field by two magnetic elements that are located in the

additional row and that are switched at time-division by the switching circuit.

[0031]

The eddy-current flaw detection device according to a ninth
5 aspect of the invention is characterized by further comprising an amplifier circuit for amplifying a signal that each of the magnetic field detection elements outputted via the switching circuit.

[0032]

The eddy-current flaw detection probe according to a tenth
10 aspect of the invention is an eddy-current flaw detection probe for performing eddy-current flaw detection of a conductive pipe, and comprising: a magnetic element group of which a specified number of elements are evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is
15 formed such that it can be inserted into the conductive pipe, with one of the two rows being located at a position that differs from that of the other row by $1/2$ the even spacing in the row direction; and switching circuits for switching the magnetic elements in the respective row of the magnetic element group at time-division, and
20 is characterized in that the magnetic elements in one row are constructed as magnetic field excitation elements that excite a magnetic field by being switched at time-division by the switching circuit, the magnetic elements in the other row are constructed as magnetic field detection elements that detect a magnetic field by
25 being switched at time-division by the switching circuit, and

eddy-current flaw detection of the conductive pipe is performed by detecting each magnetic field that is excited by each magnetic element that functions as the magnetic field excitation element by two the magnetic elements that function as the magnetic field detection elements and that are located at positions that differ from that of the magnetic field excitation element by $3/2$ the even spacing in the row direction.

[0033]

In the eddy-current flaw detection probe according to the tenth aspect of the invention, a magnetic element group is provided of which a specified number of elements are evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it can be inserted into a conductive pipe, with one of the two rows being located at a position that differs from that of the other row by $1/2$ the even spacing in the row direction. Eddy-current flaw detection is performed by causing the switching circuits to switch the magnetic elements in the respective row at time-division. The magnetic elements in one row function as magnetic field excitation elements that excite a magnetic field by being switched at time-division, and the magnetic elements in the other row function as magnetic field detection elements that detect a magnetic field by being switched at time-division. Eddy-current flaw detection of a conductive pipe is performed by detecting each magnetic field that is excited by each magnetic element that functions as the magnetic field

excitation element by two of the magnetic elements that function as magnetic field detection elements and that are located at positions that differ from that of the magnetic field excitation element by $3/2$ the even spacing in the row direction.

5 [0034]

The eddy-current flaw detection probe according to an eleventh aspect of the invention is an eddy-current flaw detection probe for performing eddy-current flaw detection of a conductive pipe, and comprising: a magnetic element group of which a
10 specified number of elements are evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it can be inserted into the conductive pipe, with one of the two rows being located at a position that differs from that of the other row by $1/2$ the even
15 spacing in the row direction; and switching circuits for switching the magnetic elements in the respective row of the magnetic element group at time-division, and is characterized in that the magnetic elements in one row are magnetic field excitation elements that excite a magnetic field, the magnetic elements in the
20 other row are magnetic field detection elements that detect a magnetic field, and eddy-current flaw detection of the conductive pipe is performed by detecting each magnetic field that is excited by each magnetic field excitation element that is switched at time-division by the switching circuit by two magnetic field
25 detection elements that are each located in the other row at

positions that differ from the magnetic field excitation element by $3/2$ the even spacing in the row direction and that are switched at time-division by the switching circuit.

[0035]

5 In the eddy-current flaw detection probe according to the eleventh aspect of the invention, a magnetic element group is provided of which a specified number of magnetic elements are evenly spaced in each of at least two rows that are formed around the surface of a column shaped casing that is formed such that it
10 can be inserted into a conductive pipe, with one of the two rows being located at a position that differs from that of the other row by $1/2$ the even spacing in the row direction. Eddy-current flaw detection is performed by causing the switching circuits to switch the magnetic elements in the respective row at time-division. The
15 magnetic elements in one row are magnetic field excitation elements that excite a magnetic field, and the magnetic elements in the other row are magnetic field detection elements that detect a magnetic field. Eddy-current flaw detection of the conductive pipe is performed by detecting each magnetic field that is excited by
20 each magnetic field excitation element that is switched at time-division by two magnetic field detection elements that are each located in the other row at positions that differ from that of the magnetic field excitation element by $3/2$ the even spacing in the row direction and that are switched at time-division.

[0036]

The eddy-current flaw detection probe according to a twelfth aspect of the invention is an eddy-current flaw detection probe that comprises: a magnetic element group of which a
5 specified number of elements are evenly spaced in each of at least two rows, with one of the two rows being located at a position that differs from that of the other row by $1/2$ the even spacing in the row direction; and switching circuits for switching the magnetic elements in the respective row of the magnetic element group at
10 time-division, and is characterized in that the magnetic elements in one row are constructed as magnetic field excitation elements that excite a magnetic field by being switched at time-division by the switching circuit, the magnetic elements in the other row are constructed as magnetic field detection elements that detect a
15 magnetic field by being switched at time-division by the switching circuit, and eddy-current flaw detection is performed by detecting each magnetic field that is excited by each magnetic element that functions as a magnetic field excitation element by one or two of the magnetic elements that function as the magnetic field detection
20 elements and that are located at positions that differ from that of the magnetic field excitation element by $3/2$ the even spacing in the row direction.

[0037]

In the eddy-current flaw detection probe according to the
25 twelfth aspect of the invention, a magnetic element group is

provided of which a specified number of magnetic elements are evenly spaced in each of at least two rows, with one of the two rows being located at a position that differs from that of the other row by $1/2$ the even spacing in the row direction, and each switching
5 circuit switches the magnetic elements in the respective row at time-division. The magnetic elements in one row function as magnetic field excitation elements that excite a magnetic field by being switched at time-division, and the magnetic elements in the other row function as magnetic field detection elements that detect
10 a magnetic field by being switched at time-division. Eddy-current flaw detection is performed by detecting each magnetic field that is excited by each magnetic element that functions as the magnetic field excitation element by one or two of the magnetic elements that function as the magnetic field detection elements and that are
15 located at positions that differ from that of the magnetic field excitation element by $3/2$ the even spacing in the row direction.
[0038]

The eddy-current flaw detection probe according to a thirteenth aspect of the invention is an eddy-current flaw detection
20 probe that comprises: a magnetic element group of which a specified number of elements are evenly spaced in each of at least two rows, with one of the two rows being located at a position that differs from that of the other row by $1/2$ the even spacing in the row direction; and switching circuits for switching the magnetic
25 elements in the respective row of the magnetic element group at

time-division, and is characterized in that the magnetic elements in one row are magnetic field excitation elements that excite a magnetic field, the magnetic elements in the other row are magnetic field detection elements that detect a magnetic field, and
5 eddy-current flaw detection is performed by detecting each magnetic field that is excited by each magnetic field excitation element that is switched at time-division by the switching circuit by one or two magnetic field detection elements that are each located in the other row at positions that differ from the magnetic
10 field excitation element by $3/2$ the even spacing in the row direction and that are switched at time-division by the switching circuit.
[0039]

In the eddy-current flaw detection probe according to the thirteenth aspect of the invention, a magnetic element group is
15 provided of which a specified number of magnetic elements are evenly spaced in each of at least two rows, with one of the two rows being located at a position that differs from that of the other row by $1/2$ the even spacing in the row direction, each switching circuit switches the magnetic elements in the respective row at
20 time-division. The magnetic elements in one row are magnetic field excitation elements that excite a magnetic field, and the magnetic elements in the other row are magnetic field detection elements that detect a magnetic field. Eddy-current flaw
25 detection is performed by detecting each magnetic field that is excited by each magnetic field excitation element that is switched

at time-division by one or two magnetic field detection elements that are each located in the other row at positions that differ from that of the magnetic field excitation element by $3/2$ the even spacing in the row direction and that are switched at time-division.

5 [0040]

The eddy-current flaw detection probe according to a fourteenth aspect of the invention is characterized by further comprising: a magnetic element group that is located in a row around the surface of the casing adjacent to the other row; and a
10 switching circuit for switching the magnetic element group at time-division, and performing eddy-current flaw detection by detecting the excited magnetic field by two magnetic elements that are located in the row and that are switched at time-division.

[0041]

15 In the eddy-current flaw detection probe according to the fourteenth aspect of the invention, a magnetic element group is additionally provided in a row around the surface of the casing adjacent to the other row, and an additionally provided switching circuit switches the additionally provided magnetic element group
20 at time-division. Eddy-current flaw detection is performed by detecting the excited magnetic field by switching two magnetic elements of that magnetic element group at time-division.

[0042]

The eddy-current flaw detection probe according to a
25 fifteenth aspect of the invention is characterized by further

comprising an amplifier circuit for amplifying a signal that each of the magnetic field detection elements outputted via a switching circuit.

[0043]

5 With the eddy-current flaw detection method according to the first to third aspects of the invention, it is possible to provide an eddy-current flaw detection method that improves the spatial resolution of flaw detection signals as well as signal reproducibility during redetection of flaws, and reduces signal interference due to
10 crosstalk with a simple circuit construction.

[0044]

 With the eddy-current flaw detection device according to the fourth to ninth aspects of the invention, it is possible to provide an eddy-current flaw detection device that improves the spatial
15 resolution of flaw detection signals as well as signal reproducibility during redetection of flaws, and reduces signal interference due to crosstalk with a simple circuit construction.

[0045]

 With the eddy-current flaw detection probe according to
20 the tenth to fifteenth aspects of the invention, it is possible to provide an eddy-current flaw detection probe that improves the spatial resolution of flaw detection signals as well as signal reproducibility during redetection of flaws, and reduces signal interference due to crosstalk with a simple circuit construction.

BRIEF DESCRIPTION OF THE SEVERAL VIEWS OF THE
DRAWINGS

[0046]

5 FIG. 1 is a perspective drawing schematically illustrating
the external appearance of a conventional eddy-current flaw
detection probe;

 FIG. 2 is a block diagram illustrating the circuit
construction inside the casing of a conventional eddy-current flaw
10 detection probe and eddy-current flaw detection device;

 FIG. 3A is an expanded view explaining the operation of a
conventional eddy-current flaw detection probe during a first
timeslot, and illustrating a planar expansion of the coils shown in
FIG. 1;

15 FIG. 3B is an expanded view explaining the operation of a
conventional eddy-current flaw detection probe during a second
timeslot, and illustrating a planar expansion of the coils shown in
FIG. 1;

 FIG. 3C is an expanded view explaining the operation of a
20 conventional eddy-current flaw detection probe during a fifteenth
timeslot, and illustrating a planar expansion of the coils shown in
FIG. 1;

 FIG. 3D is an expanded view explaining the operation of a
conventional eddy-current flaw detection probe during a sixteenth
25 timeslot, and illustrating a planar expansion of the coils shown in

FIG. 1;

FIG. 4 is a perspective drawing schematically illustrating the external appearance of an eddy-current flaw detection probe that is used in an embodiment of a eddy-current flaw detection method, eddy-current flaw detection device and eddy-current flaw
5 detection probe of the present invention;

FIG. 5 is a block diagram illustrating circuit construction inside the casing of an eddy-current flaw detection probe and eddy-current flaw detection device of the present invention;

10 FIG. 6A is an expanded view explaining the operation of the eddy-current flaw detection method, eddy-current flaw detection device and eddy-current flaw detection probe of the present invention during a first timeslot, and illustrating a planar expansion of the coils shown in FIG. 4;

15 FIG. 6B is an expanded view explaining the operation of the eddy-current flaw detection method, eddy-current flaw detection device and eddy-current flaw detection probe of the present invention during a second timeslot, and illustrating a planar expansion of the coils shown in FIG. 4;

20 FIG. 6C is an expanded view explaining the operation of the eddy-current flaw detection method, eddy-current flaw detection device and eddy-current flaw detection probe of the present invention during a seventh timeslot, and illustrating a planar expansion of the coils shown in FIG. 4; and

25 FIG. 6D is an expanded view explaining the operation of

the eddy-current flaw detection method, eddy-current flaw detection device and eddy-current flaw detection probe of the present invention during an eighth timeslot, and illustrating a planar expansion of the coils shown in FIG. 4.

5

DETAILED DESCRIPTION

[0048]

The following description will explain the present invention in detail on the basis of the drawings illustrating some embodiments thereof.

[0049]

FIG. 4 is a perspective drawing schematically illustrating the external appearance of an eddy-current flaw detection probe that is used in an embodiment of the eddy-current flaw detection method, eddy-current flaw detection device and eddy-current flaw detection probe of the present invention.

This eddy-current flaw detection probe comprises a column shaped casing (housing) 41 that is formed such that it can be gently inserted inside a slim metal pipe, and eight coils 11 to 18, 21 to 28, 31 to 38, that are aligned around the outer surface of the casing 41, are evenly spaced in each of three rows. The coils 11 to 18 of the first row of the three rows are arranged such that they are located at a position in the circumferential direction that differs from that of the coils 21 to 28 and 31 to 38 of the other two rows by 1/2 the

equal spacing.

[0050]

FIG. 5 is a block diagram illustrating the circuit construction inside the casing 41 and eddy-current flaw detection device.

The coils (magnetic elements, magnetic field excitation means) 11 to 18 in the first row are coils that are used as magnetic field excitation coils (magnetic field excitation elements) that generate an eddy current in the thickness section from the inner surface of a slim metal pipe, and each is connected to a multiplexer (switching circuit) 51 for magnetic field excitation.

A lead wire 56 is connected to the multiplexer 51 for magnetic field excitation, and an AC current for exciting a magnetic field is applied to the lead wire 56 from the main unit 59 of the eddy-current flaw detection device.

[0051]

Moreover, the coils (magnetic elements, magnetic field detection means) 21 to 28 in the second row are coils that are used as magnetic field detection coils (magnetic field detection elements) that detect a magnetic field according to an eddy current that is generated in the thickness section of a slim metal pipe, and each is connected to a multiplexer (switching circuit) 52 for magnetic field detection. An amplifier (magnetic field detection means) 54, which amplifies the output signals of the magnetic field that is detected by the coils 21 to 28, is connected to the multiplexer 52 for

magnetic field detection, and the amplified signal from the amplifier 54 is outputted to the main unit 59 of the eddy-current flaw detection device via a lead wire 57.

[0052]

5 The coils (magnetic elements, magnetic field detection means) 31 to 38 in the third row are coils used for magnetic field detection, and each is connected to a multiplexer (switching circuit) 53 for magnetic field detection. An amplifier (magnetic field detection means) 55, which amplifies the output signal of the magnetic field that is detected by the coils 31 to 38, is connected to the multiplexer 53 for magnetic field detection, and the amplified signal from the amplifier 55 is outputted to the main unit 59 of the eddy-current flaw detection device via a lead wire 58.

[0053]

15 As shown in FIG. 4, the lead wires 56 to 58 are stored inside a cable 42 that connects the center section of the surface on one end of the casing 41 of the eddy-current flaw detection probe with the main unit 59 of the eddy-current flaw detection device.

 An oscillation circuit (magnetic field excitation means) 60 that generates an AC current for exciting a magnetic field by the coils 11 to 18, a signal detection circuit 61 that obtains amplified detection signals of magnetic fields they are detected by coils 21 to 28 and 31 to 38, and a communication unit 62 for communicating with a personal computer (or workstation) 63 are located inside of the main unit 59 of the eddy-current flaw detection device. The

personal computer 63 receives the detection signal that was obtained by the signal detection circuit 61 via the communication unit 62 as detection data, and records and displays the received detection data.

5 The amplifiers 54 and 55 can also be located inside of the main unit 59 of the eddy-current flaw detection device, and when a small number of coils are in each row, the multiplexers 51 to 53 could also be located inside of the main unit 59 of the eddy-current flaw detection device.

10 [0054]

FIGS. 6A to 6D are expanded views explaining the operation of an eddy-current flaw detection probe having this kind of construction, and illustrating a planar expansion of the coils 11 to 18, 21 to 28 and 31 to 38 shown in FIG. 4.

15 This eddy-current flaw detection probe detects flaws for the amount of one circumference of the inner surface of a slim metal pipe in first through eighth timeslots indicating the cycle of the operation.

 According to the eddy-current flaw detection probe, in the
20 first timeslot (FIG. 6A), the multiplexer 51 selects coil 11 as the magnetic field excitation coil T, and the multiplexer 52 selects coils 28 and 23 in the second row, which are separated from the coil 11 by the amount of $3/2$ coils in the circumferential direction, as magnetic field detection coils R1 and R2. In addition, the
25 multiplexer 53 selects coils 31 and 32 in the third row, which are

separated from coil 11 by the amount of 0.5 coil in the circumferential direction, as magnetic field detection coils R3 and R4.

[0055]

5 The detection signals that are outputted by the magnetic field detection coils R1, R2 are used for detecting flaws in the circumferential direction of the slim metal pipe (direction that orthogonally crosses the advancement direction of the eddy-current flaw detection probe), and the detection signals that are outputted
10 by the magnetic field detection coils R3, R4 are used for detecting flaws in the axial direction of the slim metal pipe (advancement direction of the eddy-current flaw detection probe).

[0056]

 According to the eddy-current flaw detection probe, in the
15 second timeslot (FIG. 6B), the multiplexer 51 selects coil 12 as the magnetic field excitation coil T, and the multiplexer 52 selects coils 21 and 24 in the second row, which are separated from the coil 12 by the amount of $3/2$ coils in the circumferential direction, as magnetic field detection coils R1 and R2. In addition, the
20 multiplexer 53 selects coils 32 and 33 in the third row, which are separated from coil 12 by the amount of 0.5 coil in the circumferential direction, as magnetic field detection coils R3 and R4.

[0057]

25 In each timeslot after that, the multiplexer 51 sequentially

selects coils 13, 14, 15, ... as the magnetic field excitation coil T, and the multiplexer 52 sequentially selects pairs of coils 22·25, 23·26, 24·27, ...as the magnetic field detection coils R1·R2. In addition, the multiplexer 53 sequentially selects pairs of coils 33·34, 34·35, 5 35·36, ... as the magnetic field detection coils R3·R4.

[0058]

According to the eddy-current flaw detection probe, in the seventh timeslot (FIG. 6C), the multiplexer 51 selects coil 17 as the magnetic field excitation coil T, and the multiplexer 52 selects coils 10 26 and 21 in the second row, which are separated from the coil 17 by the amount of $3/2$ coils in the circumferential direction, as magnetic field detection coils R1 and R2. In addition, the multiplexer 53 selects coils 37 and 38 in the third row, which are separated from coil 17 by the amount of 0.5 coil in the 15 circumferential direction, as magnetic field detection coils R3 and R4.

[0059]

According to the eddy-current flaw detection probe, in the eighth timeslot (FIG. 6D), the multiplexer 51 selects coil 18 as the magnetic field excitation coil T, and the multiplexer 52 selects coils 20 27 and 22 in the second row, which are separated from the coil 18 by the amount of $3/2$ coils in the circumferential direction, as magnetic field detection coils R1 and R2. In addition, the multiplexer 53 selects coils 38 and 31 in the third row, which are 25 separated from coil 18 by the amount of 0.5 coil in the

circumferential direction, as magnetic field detection coils R3 and R4.

[0060]

Depending on the first through eighth timeslots described
5 above, the combinations of the magnetic field excitation coil T and
magnetic field detection coil R1, and the magnetic field excitation
coil T and magnetic field detection coil R2 are suitably located for
detecting flaws in the circumferential direction of the slim metal
pipe (direction that orthogonally crosses the advancement direction
10 of the eddy-current flaw detection probe). Also, the combinations
of the magnetic field excitation coil T and the magnetic field
detection coil R3, and the magnetic field excitation coil T and the
magnetic field detection coil R4 are suitably located for detecting
flaws in the axial direction of the slim metal pipe (advancement
15 direction of the eddy-current flaw detection probe).

[0061]

In the case of this embodiment, since output of the 16
channels by the coils 21 to 28 is obtained for the same
circumference per one circumference of the slim metal pipe, there
20 is no need for compensating for shifting in the axial direction, and
thus the spatial resolution of flaw detection signals, and the
reproducibility during redetection of flaws are improved.

Moreover, as shown in FIG. 5, when compared with the
conventional circuit shown in FIG. 2, there is no need for two
25 multiplexers, as well as there is no need for wiring from coils 11 to

18 of the first row and coils 21 to 28 of the second row to each of the two multiplexers, so the circuit construction can be made more compact, and the entire circuit can be stored inside the casing 41 of the eddy-current flaw detection probe. In addition, by reducing
5 the amount of wiring, interference signals due to crosstalk can be reduced.

[0062]

Depending on the performance and the like of the eddy-current flaw detection device, it is possible to combine two
10 timeslots. For example, in the first timeslot, it is possible to simultaneously select coils 11 and 15 as magnetic field excitation coils, and to simultaneously select coils 31, 32, 28, 23, 35, 36, 24 and 27 as magnetic field detection coils.

An amplifier circuit is normally necessary in order to
15 amplify detection signals from the multiplexer, however, in cases where the deterioration of the detection signals is not especially a problem, it is also possible to omit the amplifier circuit.

Moreover, this embodiment illustrates an example of an insert type probe that is inserted inside a slim metal pipe, however,
20 the present invention can also be applied to a top placement type or penetrating type eddy-current flaw detection device and eddy-current flaw detection probe.

[0063]

Furthermore, in this embodiment, coils were used as both
25 magnetic field excitation elements and magnetic field detection

elements, however, the invention is not limited to this, and of course it is possible to use other elements. Also, a clear distinction is made between magnetic field excitation element groups and magnetic field detection element groups, so, for example, it is
5 possible to combine different kinds of elements such using a coil as a magnetic field excitation element and using a magnetic detection element such as a hole element, magnetic resistance effect element and the like as a magnetic field detection element.

Moreover, the direction of the coils is not limited to that
10 shown in FIG. 4, and construction using other directions is possible.

[0064]

Furthermore, the number of coils is not necessarily limited to eight coils per row, and can be suitably increased or decreased as
15 needed. In addition, similarly the number of channels of the multiplexer, which is a switching circuit, can be suitably increased or decreased as needed. Also, the most preferable location for the circuit to be located is inside the casing of the eddy-current flaw detection probe, however, in the case where that is physically
20 impossible, the circuit can be provided inside of or around the pipe that stores the wiring.

[0065]

The present invention can be applied to an eddy-current flaw detection method, eddy-current flaw detection device and
25 eddy-current flaw detection probe that are used in nondestructive

inspection (eddy-current flaw detection testing) of a heat transfer pipe inside of a heat exchanger.

CLAIMS:

1. An eddy-current flaw detection method for performing eddy-current flaw detection of a conductive pipe by using:
 - magnetic element groups of which a specified number of magnetic elements, which either excite or detect a magnetic field, are evenly spaced, by an even spacing along a circumferential direction, in each of at least two rows that are formed around a surface of a column shaped casing that is formed such that it can be inserted into the conductive pipe, with magnetic elements of a first row being located at positions that differ from magnetic elements of a second row by $1/2$ the even spacing in the circumferential direction;
 - at least one magnetic element group being located in a third row around the surface of the casing adjacent to the magnetic elements of the second row; and
 - switching circuits for switching each magnetic element in respective rows of the magnetic element groups, the method comprising:
 - causing one of the switching circuits to switch each magnetic element in the first row at a respective time slot in order to excite the magnetic field;
 - during a given time slot when a given magnetic element in the first row has excited the magnetic field, causing one of the

switching circuits to switch two magnetic elements in the second row in a sequential manner in order to detect the excited magnetic field, the two magnetic elements in the second row and being located at positions that differ from the given magnetic element in the first row by $3/2$ the even spacing in the circumferential direction; and

during the given time slot, causing one of the switching circuits to switch two magnetic elements in the third row in a sequential manner in order to detect the excited magnetic field, the two magnetic elements in the third row being located at positions that differ from the given magnetic element in the first row by $1/2$ the even spacing in the circumferential direction.

2. The eddy-current flaw detection method according to claim 1, further comprising:

preparing the magnetic elements in the first row as magnetic field excitation elements that excite the magnetic field, and the magnetic elements in the second row as magnetic field detection elements that detect the magnetic field;

causing one of the switching circuits to switch each magnetic field excitation element at the respective time slot in order to excite the magnetic field; and

during the given time slot when a given magnetic field excitation element has excited the magnetic field, causing one of the

switching circuits to switch two magnetic field detection elements in a sequential manner in order to detect the excited magnetic field, the two magnetic field detection elements being located at positions that differ from the given magnetic field excitation element by $3/2$ the even spacing in the circumferential direction.

3. An eddy-current flaw detection device comprising:

magnetic element groups of which a specified number of magnetic elements, which either excite or detect a magnetic field, are evenly spaced, by an even spacing along a placement direction, in each of at least two rows, with magnetic elements of a first row being located at positions that differ from magnetic elements of a second row by $1/2$ the even spacing in the placement direction;

at least one magnetic element group being located in a third row adjacent to the second row; and

switching circuits for switching each magnetic element in respective rows of the magnetic element groups;

magnetic field excitation means for causing the magnetic elements in the first row to function as magnetic field excitation elements that excite the magnetic field when switched at a respective time slot by one of the switching circuits; and

magnetic field detection means for causing the magnetic elements in the second row to function as magnetic field detection

elements that detect the magnetic field when switched by one of the switching circuits, wherein

the eddy-current flaw detection device is configured to execute eddy-current flaw detection by detecting each magnetic field that is excited by each magnetic field excitation element at each respective time slot by two magnetic field detection elements in a sequential manner, the two magnetic field detection elements being located at positions that differ from the exciting magnetic field excitation element by $3/2$ the even spacing in the placement direction and by detecting each excited magnetic field by two magnetic elements in the third row in a sequential manner, the two magnetic elements in the third row being located at positions that differ from the exciting magnetic field excitation element by $1/2$ the even spacing in the placement direction, the two magnetic elements in the third row being switched by one of the switching circuits.

4. The eddy-current flaw detection device according to claim 3, wherein

the magnetic elements in the first row are magnetic field excitation elements that excite the magnetic field, and

the magnetic elements in the second row are magnetic field detection elements that detect the magnetic field.

5. The eddy-current flow detection device according to claim 3 or claim 4, wherein the magnetic element groups are formed around a surface of a column shaped casing that is formed such that it can be inserted into a conductive pipe.

6. The eddy-current flow detection device according to any one of claims 3 to 5, further comprising an amplifier circuit for amplifying a signal that each of the magnetic field detection elements outputted via the switching circuit.

7. An eddy-current flow detection probe comprising:
magnetic element groups of which a specified number of magnetic elements, which either excite or detect a magnetic field, are evenly spaced, by an even spacing along a placement direction, in each of at least two rows, with magnetic elements of a first row being located at positions that differ from magnetic elements of a second row by $1/2$ the even spacing in the placement direction;

at least one magnetic element group being located in a third row adjacent to the magnetic elements of the second row; and

switching circuits for switching each magnetic element in respective rows of the magnetic element groups, wherein

the magnetic elements in the first row are constructed as magnetic field excitation elements that excite the magnetic field

when switched at a respective time slot by one of the switching circuits,

the magnetic elements in the second row are constructed as magnetic field detection elements that detect the magnetic field when switched by one of the switching circuits, and

the eddy-current flaw detection probe is configured to execute eddy-current flaw detection by detecting each magnetic field that is excited by each magnetic element that functions as a magnetic field excitation element at each respective time slot by two magnetic elements, functioning as the magnetic field detection elements, in a sequential manner and the two magnetic elements being located at positions that differ from the exciting magnetic field excitation element by $3/2$ the even spacing in the placement direction and by detecting each excited magnetic field by two magnetic elements in the third row in a sequential manner, the two magnetic elements in the third row being located at positions that differ from the exciting magnetic field excitation element by $1/2$ the even spacing in the placement direction, the two magnetic elements in the third row being switched by one of the switching circuits.

8. The eddy-current flaw detection probe according to claim 7, wherein

the magnetic elements in the first row are magnetic field

excitation elements that excite the magnetic field, and
the magnetic elements in the second row are magnetic field
detection elements that detect the magnetic field.

9. The eddy-current flaw detection probe according to claim 7
or claim 8, wherein the magnetic element groups are formed around a
surface of a column shaped casing that is formed such that it can be
inserted into a conductive pipe.

10. The eddy-current flaw detection probe according to any
one of claims 7 to 9, further comprising an amplifier circuit for
amplifying a signal that each of the magnetic field detection elements
outputted via the switching circuit.

FIG. 1

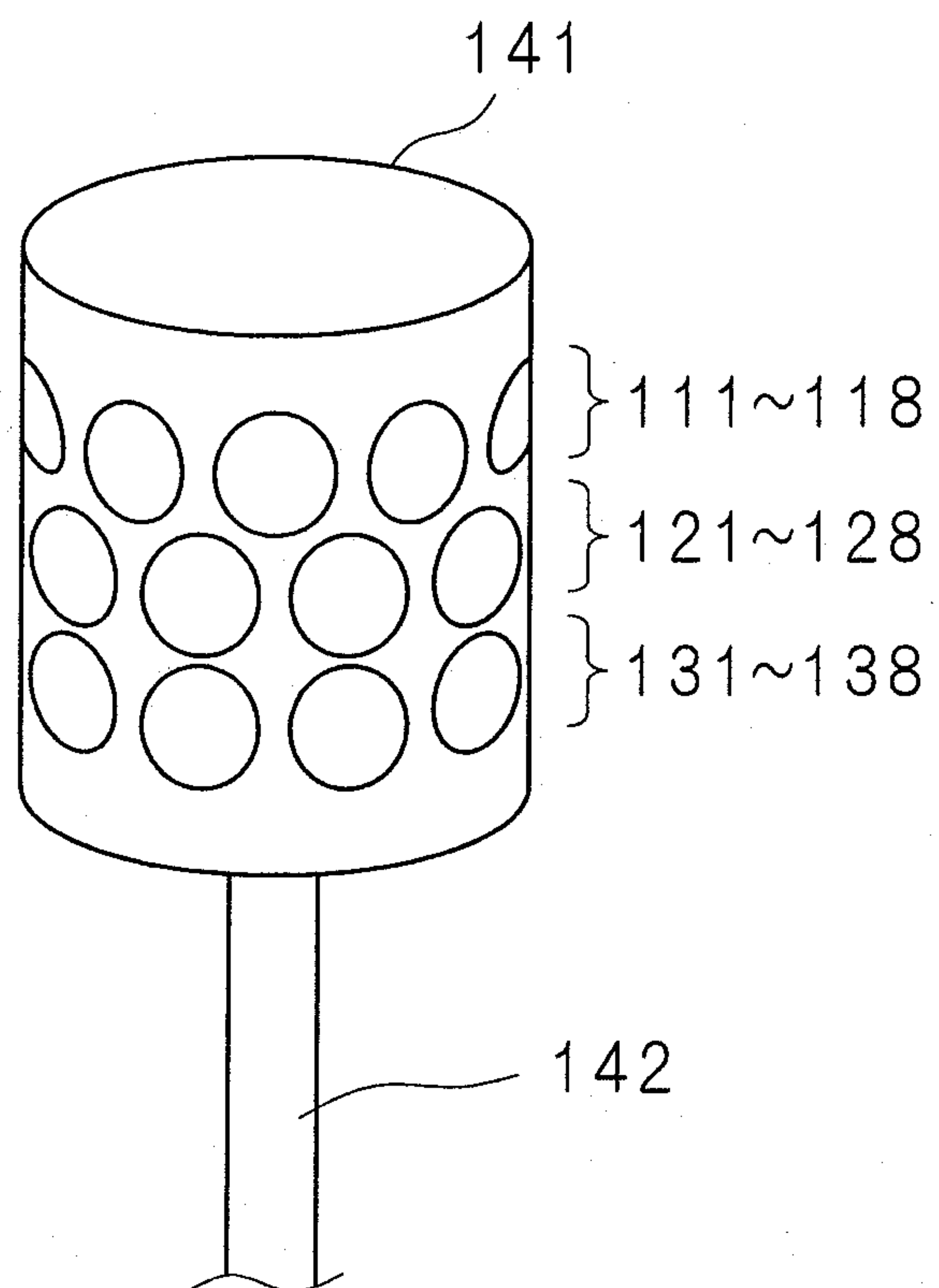


FIG. 2

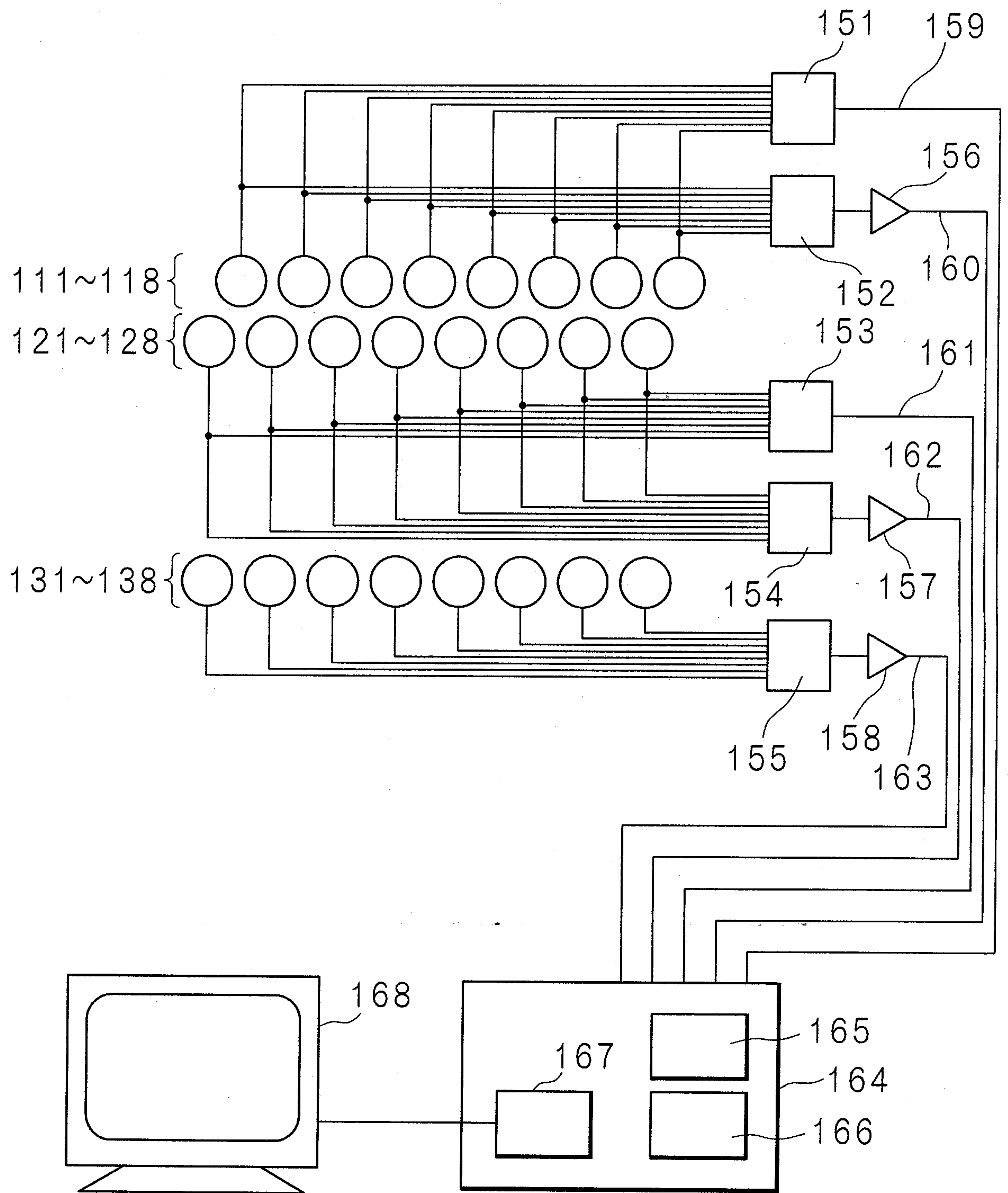


FIG. 3A

FIRST TIMESLOT

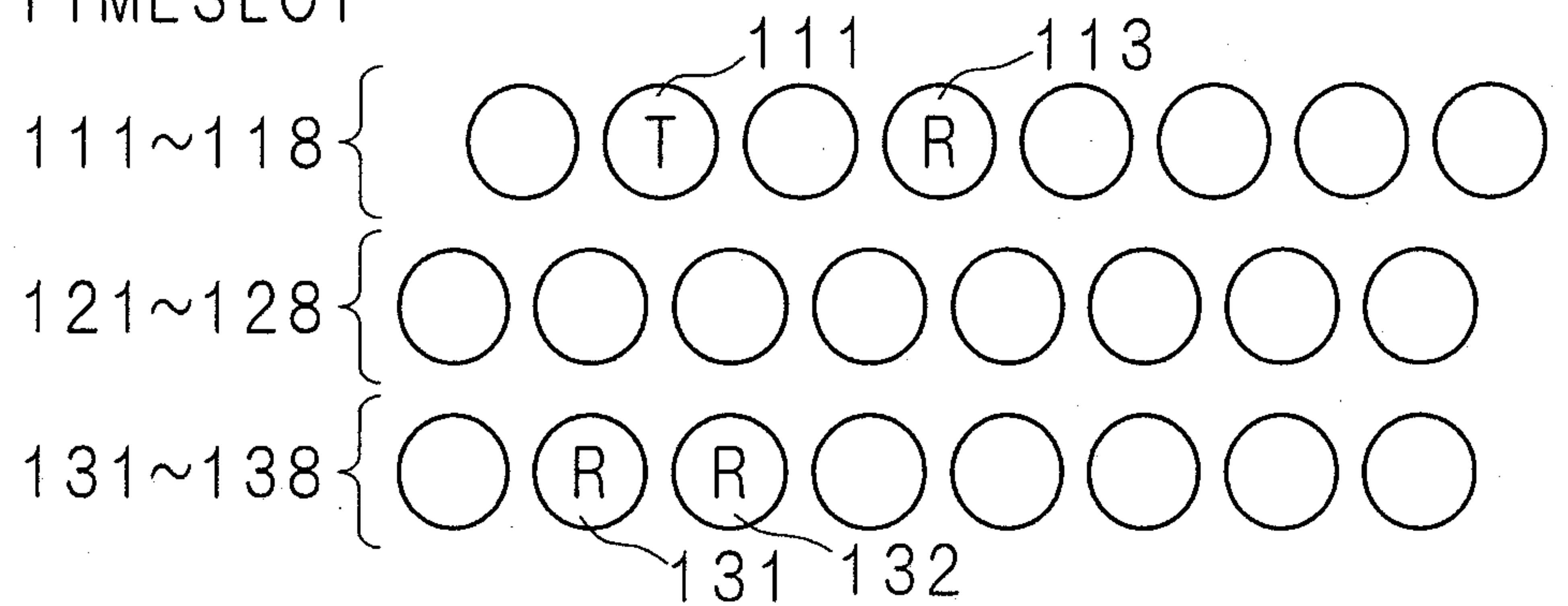


FIG. 3B

SECOND TIMESLOT

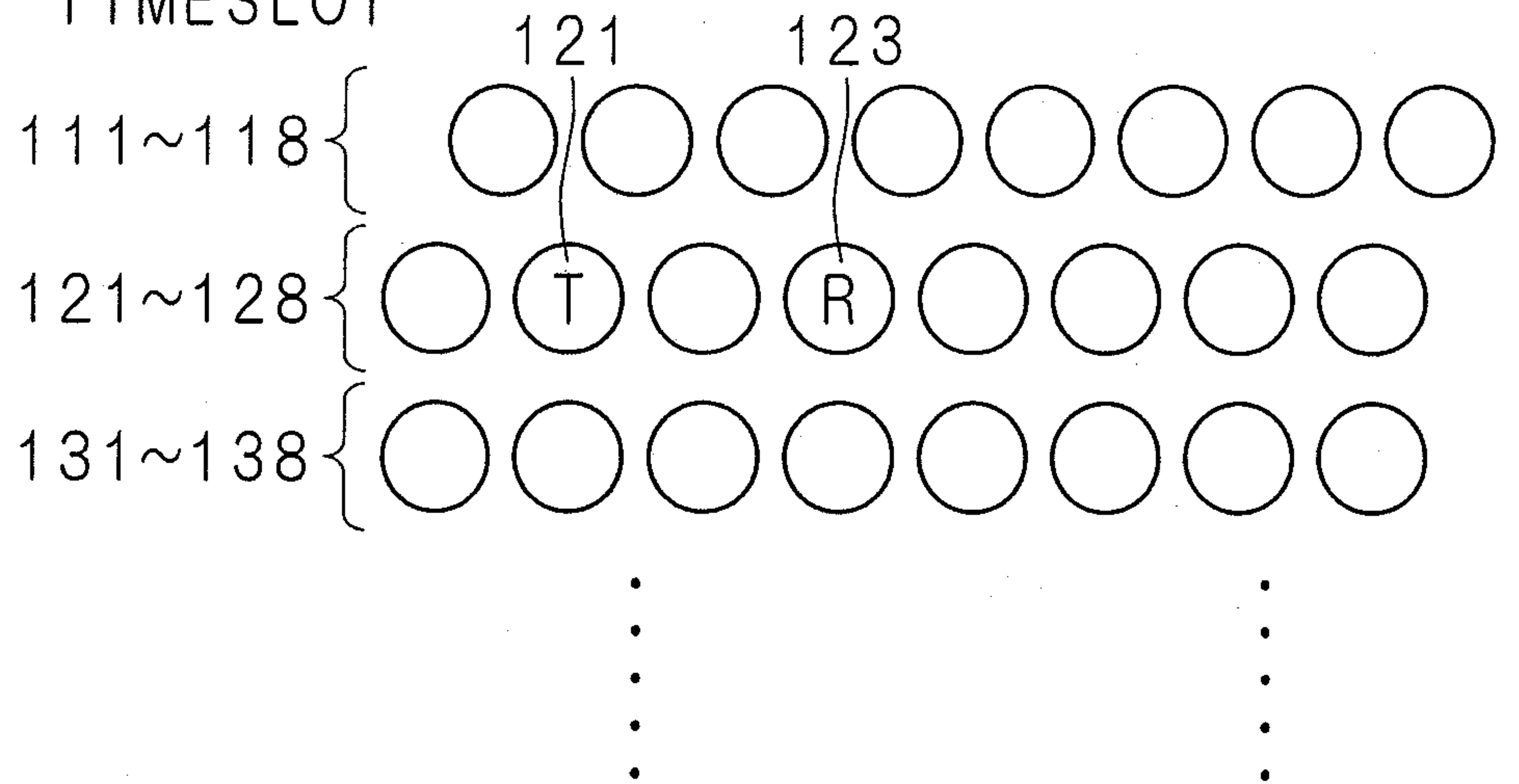


FIG. 3C

FIFTEENTH TIMESLOT

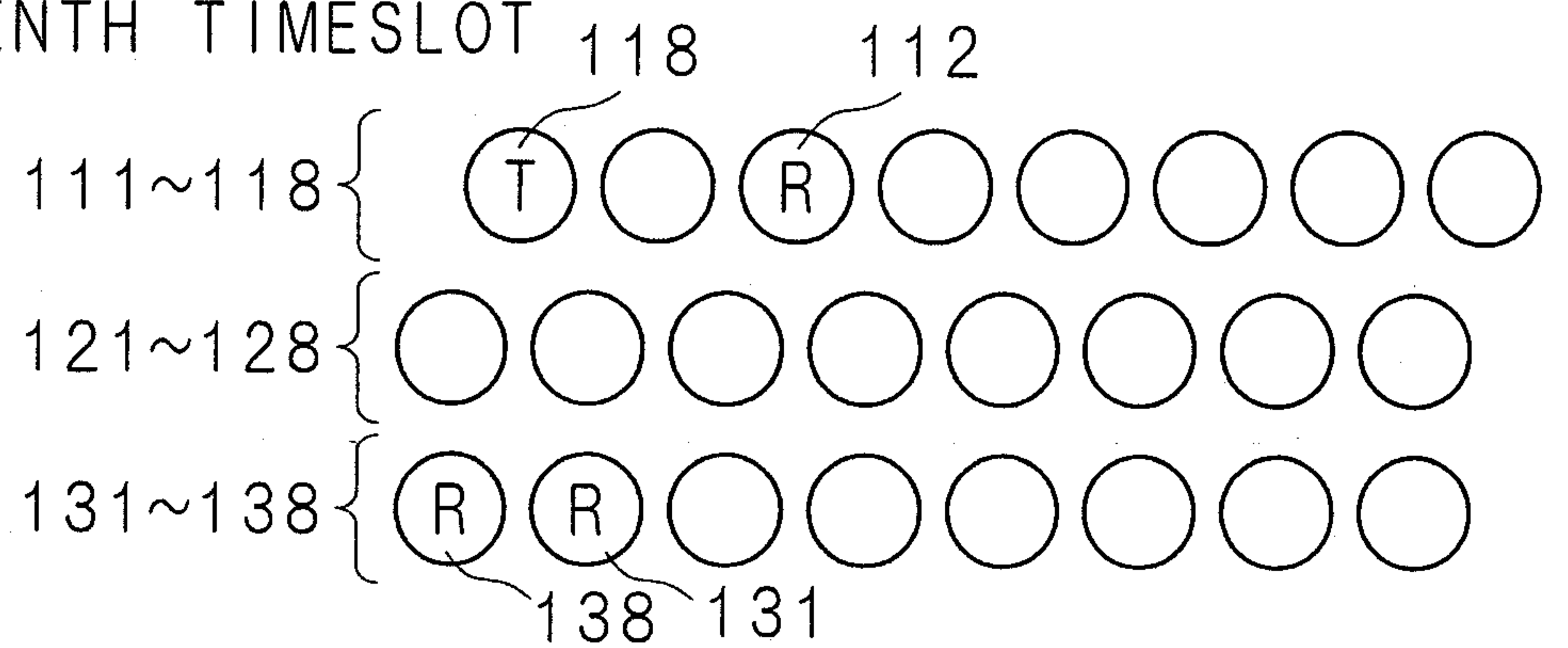


FIG. 3D

SIXTEENTH TIMESLOT

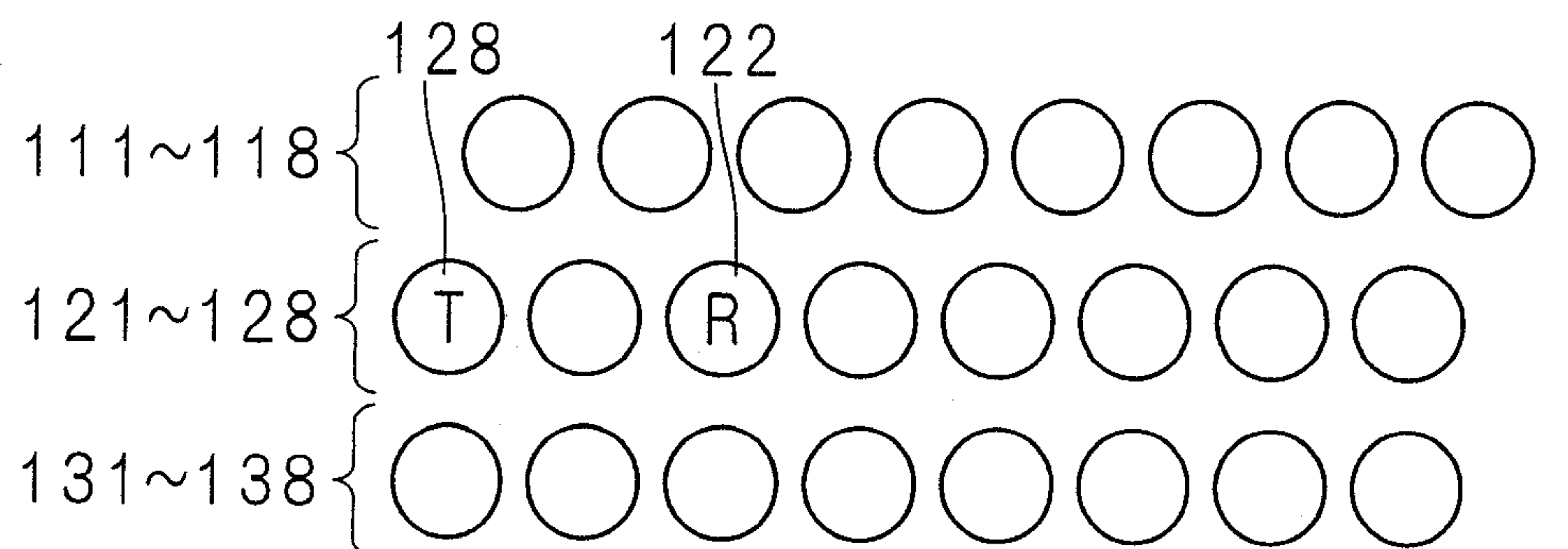


FIG. 4

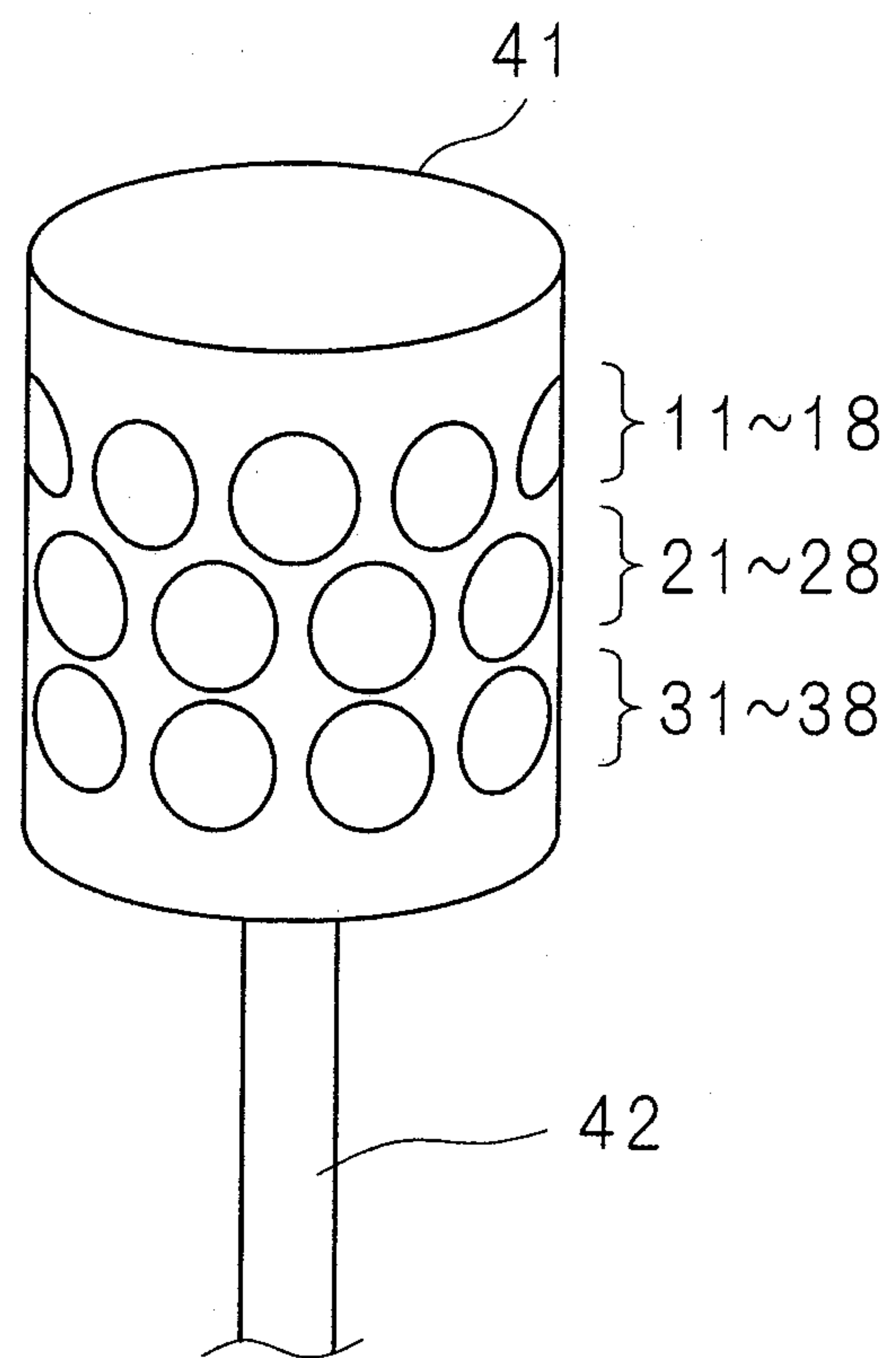


FIG. 5

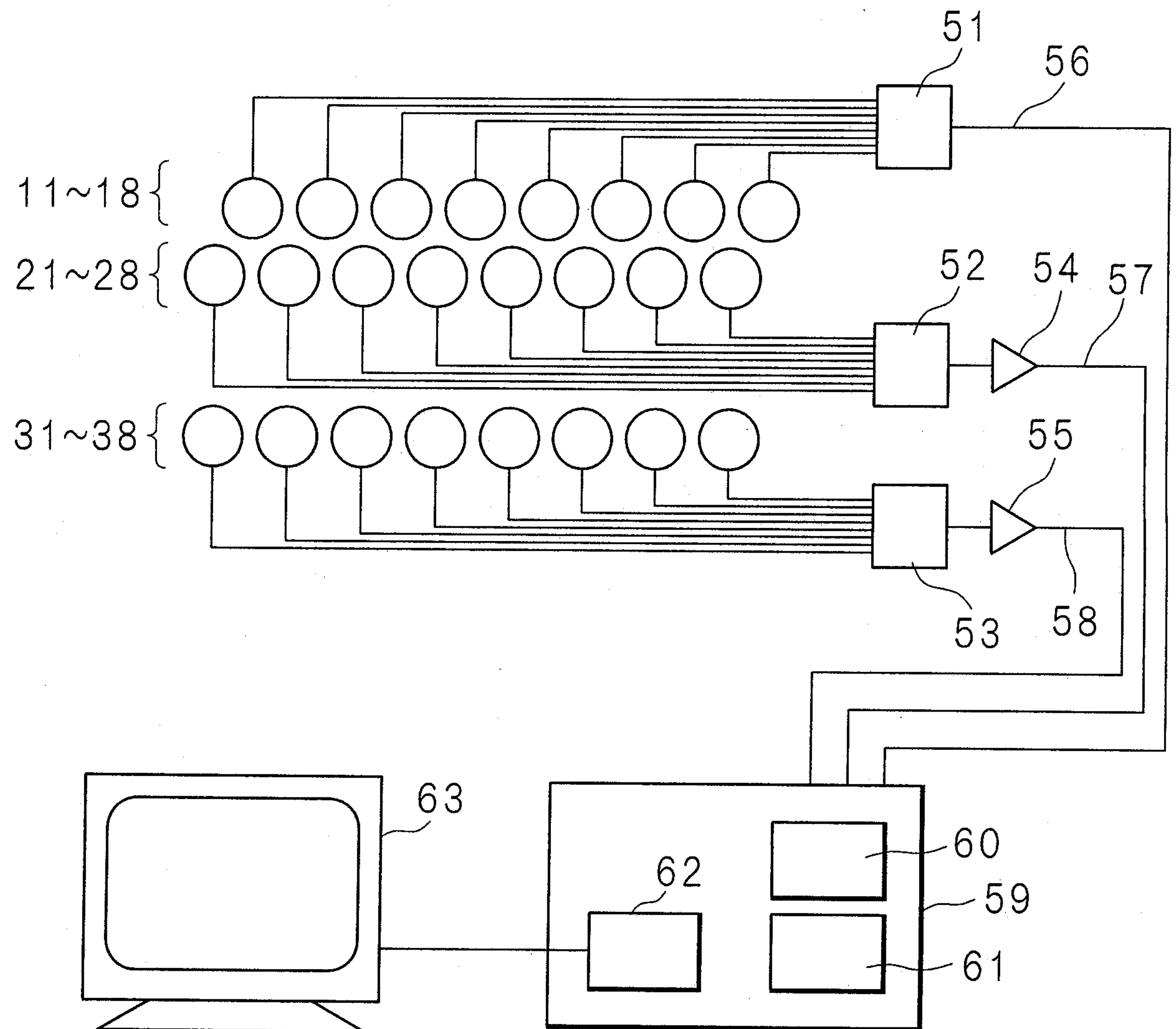


FIG. 6A

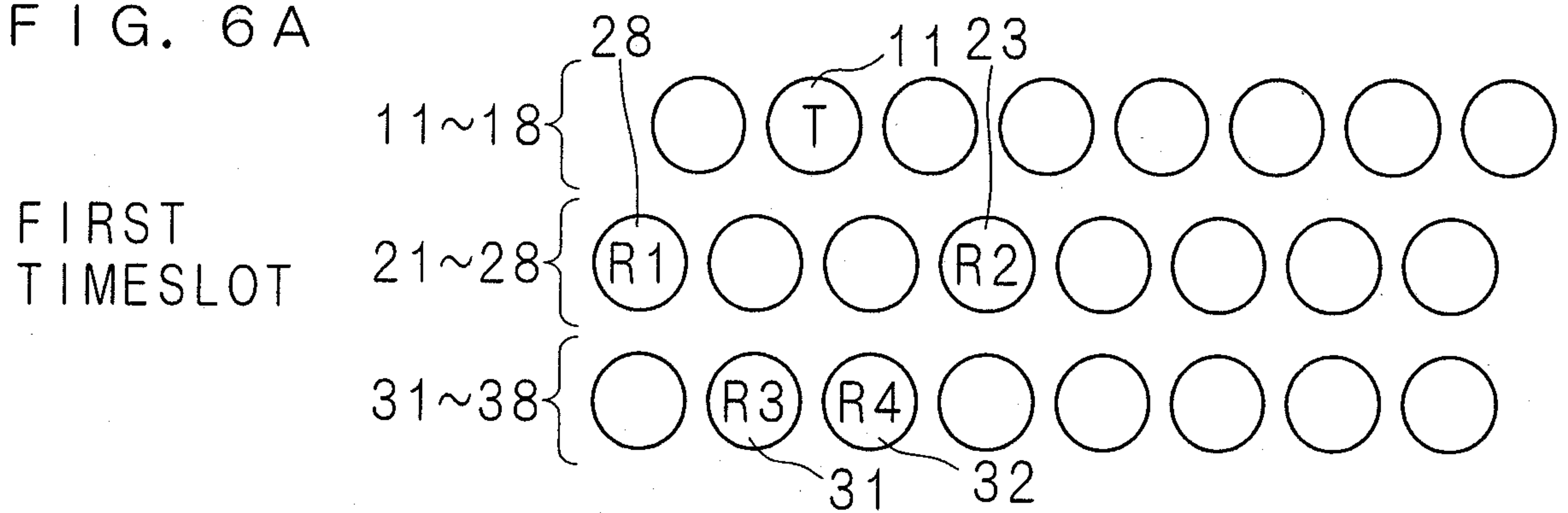


FIG. 6B

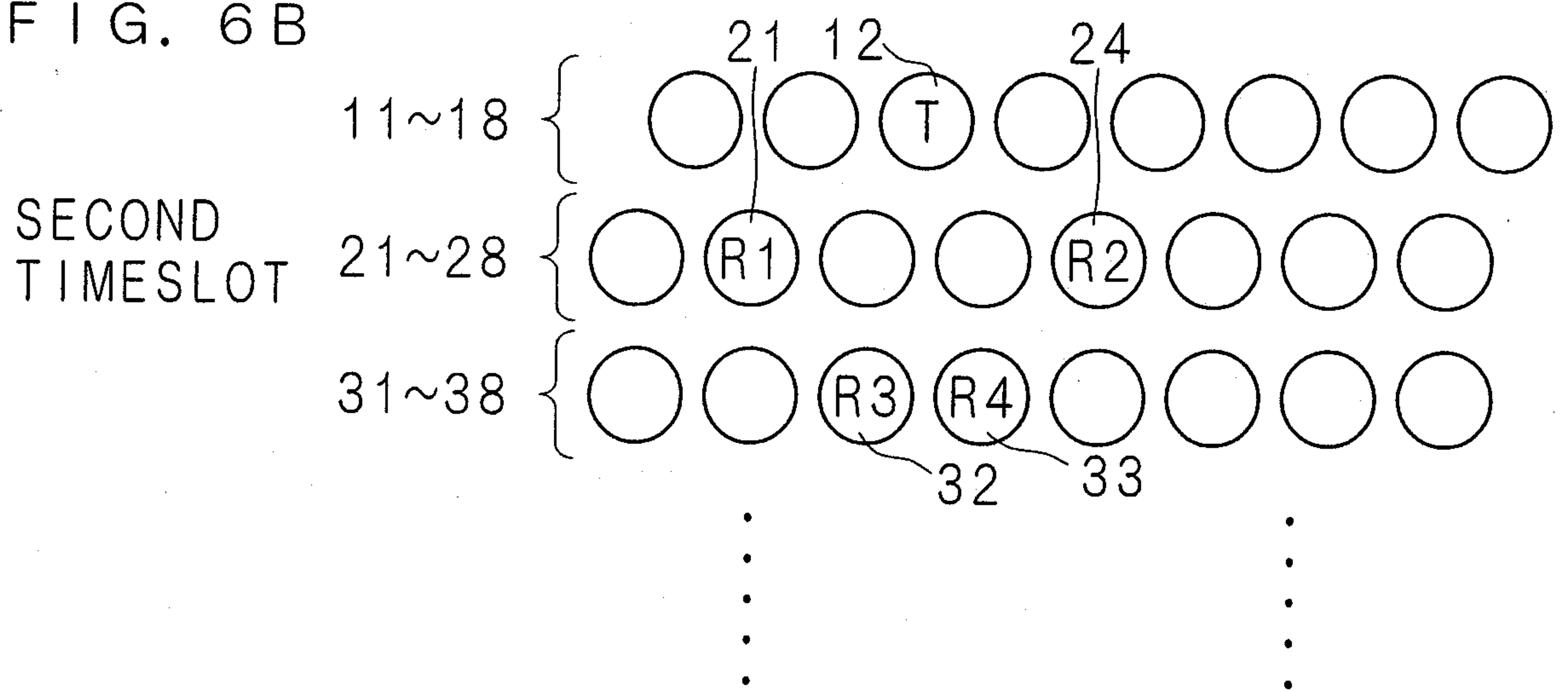


FIG. 6C

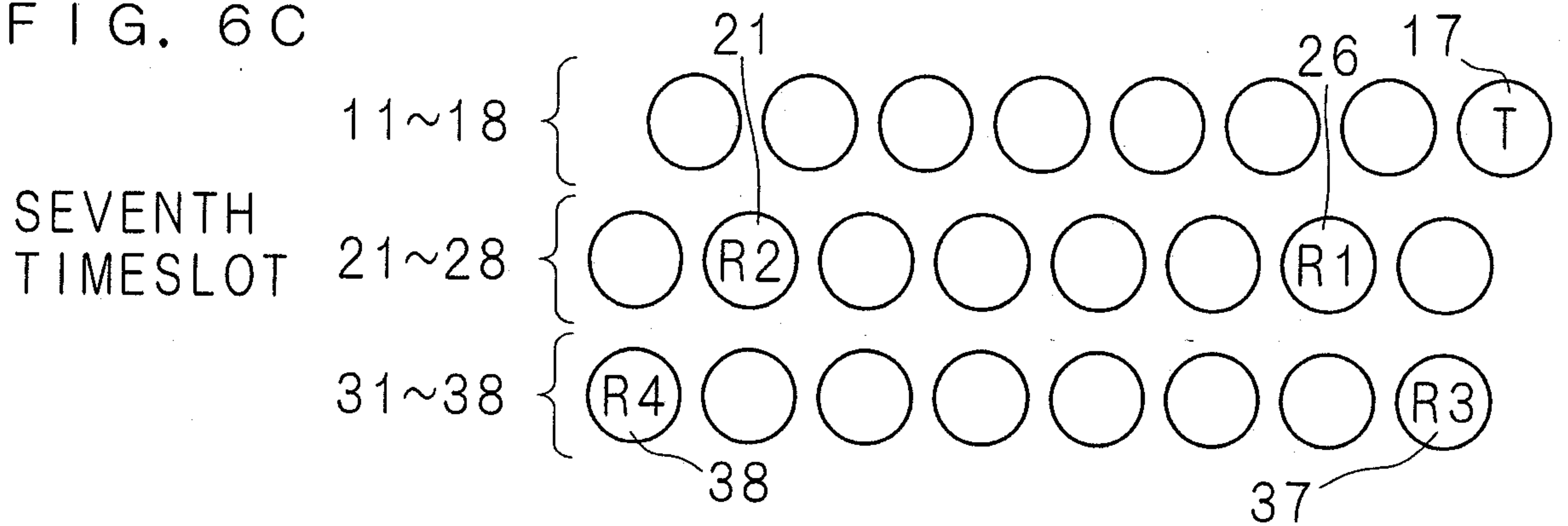
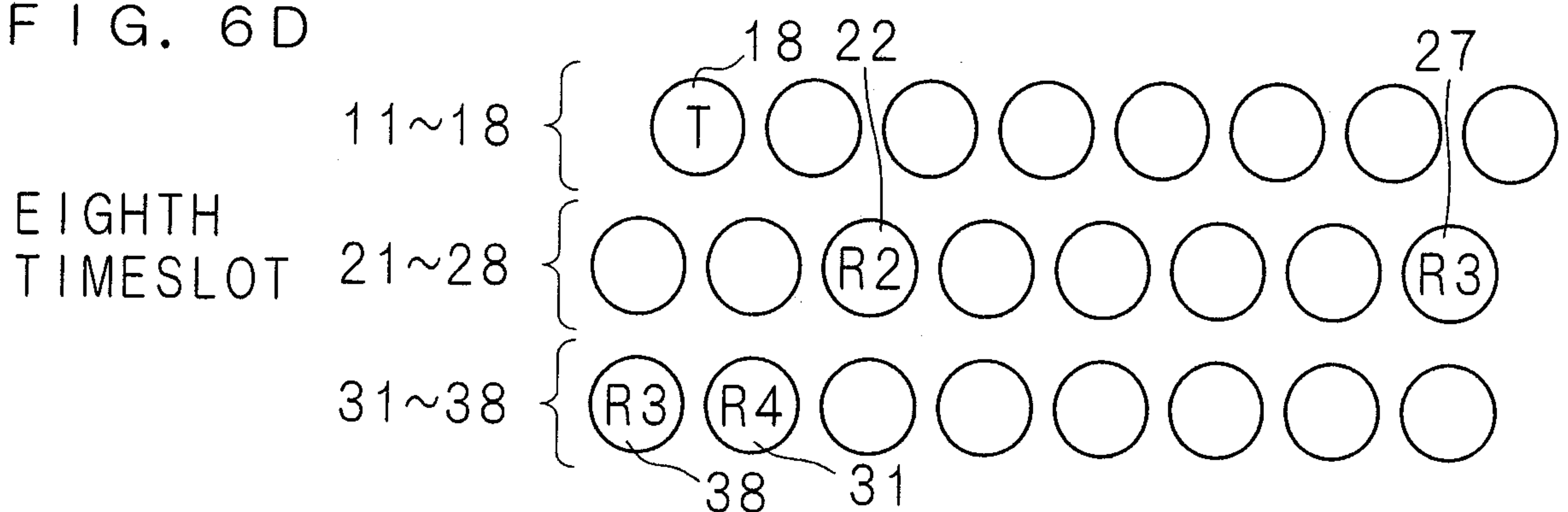


FIG. 6D



FIRST
TIMESLOT

